CHIPE E book ED

Electronic Filing System (EFS) Data

Electronic Patent Application Submission

USPTO Use Only

EFS ID:

Application ID: TRADEN

54622

10679857

Title of Invention:

METHODS AND SYSTEMS FOR

INSPECTING RETICLES USING

AERIAL IMAGING AND DIE-TO-

DATABASE DETECTION

First Named Inventor:

Stan Stokowski

Domestic/Foreign Application:

Domestic Application

Filing Date:

2003-10-06

Effective Receipt Date:

2004-02-02

Submission Type:

Information Disclosure

Statement

Filing Type:

Confirmation number:

3197

Attorney Docket Number:

5589-04001

Total Fees Authorized:

Digital Certificate Holder: cn=Kevin L. Daffer,ou=Registered Attorneys,ou=Patent and Trademark

Office,ou=Department of Commerce,o=U.S. Government,c=US

Certificate Message Digest: f646cd0a6d51973f6f6c95275e3f24fa72a344da

Electronic Version v1.1
Stylesheet Version v1.1.0

Title of Invention

METHODS AND SYSTEMS FOR INSPECTING RETICLES USING AERIAL IMAGING AND DIE-TO-DATABASE DETECTION

Application Number:

10/679857

Date:

2003-10-06

First Named Applicant:

Stan Stokowski

Confirmation Number:

3197

Attorney Docket Number: 5589-04001

I hereby certify that the use of this system is for OFFICIAL correspondence between patent applicants or their representatives and the USPTO. Fraudulent or other use besides the filing of official correspondence by authorized parties is strictly prohibited, and subject to a fine and/or imprisonment under applicable law.

I, the undersigned, certify that I have viewed a display of document(s) being electronically submitted to the United States Patent and Trademark Office, using either the USPTO provided style sheet or software, and that this is the document(s) I intend for initiation or further prosecution of a patent application noted in the submission. This document(s) will become part of the official electronic record at the USPTO.

Submitted by:	Elec. Sign.	Sign. Capacity
Kevin L. Daffer Registered Number: 34146	Kevin L. Daffer	Attorney

Documents being submitted

Files

us-ids

558904001IDS-usidst.xml

us-ids.dtd

us-ids.xsl

Comments

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18 Stylesheet Version v18.0



Title of Invention METHODS AND SYSTEMS FOR INSPECTING RETICLES USING AERIAL IMAGING AND DIE-TO-DATABASE DETECTION

Application Number:

10/679857

Confirmation Number:

3197

First Named Applicant:

Stan Stokowski

Attorney Docket Number: 5589-04001

Search string:

(5980187 or 5619548 or 6104835 or 6233719 or 5991699 or 5689614 or 4247203 or 4347001 or 4378159 or 4448532 or 4532650 or 4555798 or 4579455 or 4633504 or 4641967 or 4758094 or 4766324 or 4805123 or 4845558 or 4877326 or 4926489 or 5189481 or 5563702 or 5572598 or 5737072 or 5889593 or 6052478 or 6076465 or 6122046 or 6137570 or 6141038 or 6175645

or 6282309 or 6363166).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	5980187	1999-11-09	Verhovsky			
	2	5619548	1997-04-08	Koppel			
	3	6104835	2000-08-15	Han			
	4	6233719	2001-05-15	Hardikar et al.			
	5	5991699	1999-11-23	Kulkarni et al.			
	6	5689614	1997-11-18	Gronet et al.			
	7	4247203	1981-01-27	Levy et al.			
	8	4347001	1982-08-31	Levy et al.			
	9	4378159	1983-03-29	Galbraith			
	10	4448532	1984-05-15	Joseph et al.			
	11	4532650	1985-07-30	Wihl et al.			
	12	4555798	1985-11-26	Broadbent, Jr. et al.			

	13	4579455	1986-04-01	Levy et al.
	14	4633504	1986-12-30	Wihl
	15	4641967	1987-02-10	Pecen
	16	4758094	1988-07-19	Wihl
	17	4766324	1988-08-23	Saadat et al:
	8	4805123	1989-02-14	Specht et al.
	9	4845558	1989-07-04	Tsai et al.
2	20	4877326	1989-10-31	Chadwick et al.
	21	4926489	1990-05-15	Danielson et al.
2	22	5189481	1993-02-23	Jann et al.
	23	5563702	1996-10-08	Emery et al.
	24	5572598	1996-11-05	Wihl et al.
2	25	5737072	1998-04-07	Emery et al.
	26	5889593	1999-03-30	Bareket
	27	6052478	2000-04-18	Wihl et al.
	28	6076465	2000-06-20	Vacca et al.
	29	6122046	2000-09-19	Almogy
3	30	6137570	2000-10-24	Chuang et al.
3	31	6141038	2000-10-31	Young et al.
3	32	6175645	2001-01-16	Elyasaf et al.
3	33	6282309	2001-08-28	Emery
3	34	6363166	2002-03-26	Wihl et al.

Signature

Examiner Name	Date